Offset Centerline Caliper SERIES 536 — Vernier Type

 Specially designed for center-to-center hole diameter measurements on the same and offset planes. The beam-mounted jaw can be adjusted to facilitate the measurement of stepped sections.



SPECIFICATIONS

Metric Analog model				
Code No.	Range (mm)	Graduation (mm)	Maximum permissible error (mm)*	
Code No.	Nange (min)	Graduation (mm)	Емре	Smpe
536-105	10.1 - 150	0.05		±0.05
536-106	10.1 - 200			
536-107	10.1 - 300			±0.08

^{*} The Partial Surface Contact Error (EMPE) and Shift Error (SMPE) are terms defined by ISO 13385-1:2019.

DIMENSIONS



